

ZHE JIANG JIAJIA RIDE-ON CO., LTD TEST REPORT

SCOPE OF WORK: EMC directive (2014/30/EU) – EMC report

Model: JE1001

REPORT NUMBER 191102430SHA-001

ISSUE DATE December 4, 2019

DOCUMENT CONTROL NUMBER TTRF55014-01_V1 © 2018 Intertek





Telephone: 86 21 6127 8200 www.intertek.com

Report no. 191102430SHA-001

Applicant	:	ZHE JIANG JIAJIA RIDE-ON CO., LTD Xincang industrial Zone Pinghu City, Zhejiang Province, China
Manufacturer	:	ZHE JIANG JIAJIA RIDE-ON CO., LTD Xincang industrial Zone Pinghu City, Zhejiang Province, China
Manufacturing site	:	ZHE JIANG JIAJIA RIDE-ON CO., LTD Xincang industrial Zone Pinghu City, Zhejiang Province, China

Summary

The equipment complies with the requirements according to the following standard(s) or Specification:

EN 55014-1:2017: Electromagnetic compatibility - Requirements for household appliances, electric tools and similar apparatus Part 1: Emission

EN 55014-2:2015: Electromagnetic compatibility - Requirements for household appliances, electric tools and similar apparatus Part 2: Immunity – Product family standard

EN 61000-3-2:2014: Electromagnetic compatibility (EMC) - Part 3-2: Limits - Limits for harmonic current emissions (equipment input current \leq 16A per phase)

EN 61000-3-3:2013: Electromagnetic compatibility (EMC) - Part 3-3: Limits - Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current \leq 16A per phase and not subject to conditional connection

PREPARED BY:

REVIEWED BY:

Shen

Mark Shen

Project Engineer

Howley Zhang

Charles Zhang

Reviewer

This report is for the exclusive use of Intertek's Client and is provided pursuant to the agreement between Intertek and its Client. Intertek's responsibility and liability are limited to the terms and conditions of the agreement. Intertek assumes no liability to any party, other than to the Client in accordance with the agreement, for any loss, expense or damage occasioned by the use of this report. Only the Client is authorized to permit copying or distribution of this report and then only in its entirety. Any use of the Intertek name or one of its marks for the sale or advertisement of the tested material, product or service must first be approved in writing by Intertek. The observations and test results in this report are relevant only to the sample tested. This report by itself does not imply that the material, product, or service is or has ever been under an Intertek certification program.

TTRF55014-01_V1 © 2018 Intertek



Contents

MEASUREMENT RESULT SUMMARY	6
1. GENERAL INFORMATION	7
1.1 DESCRIPTION OF EQUIPMENT UNDER TEST (EUT)	7
1.2 DESCRIPTION OF TEST FACILITY	
2. TEST SPECIFICATIONS	9
2.1 Normative Standards	9
2.2 Mode of operation during the test	
2.3 Test Peripherals used	
2.4 RECORD OF CLIMATIC CONDITIONS	
2.5 INSTRUMENT LIST	1
2.6 Measurement Uncertainty1	3
EMISSION TEST	4
3. MAINS/LOAD/CONTROL TERMINAL CONTINUOUS DISTURBANCE VOLTAGE	4
3.1 TERMINAL VOLTAGE LIMITS FOR THE FREQUENCY RANGE 9KHZ TO 30MHZ	4
3.1.1 General limits	
3.1.2 Limits for mains port of tools	
3.2 Block Diagram of Test Setup	
3.3 TEST SETUP AND TEST PROCEDURE	
3.4 Test Protocol	7
4. MAINS TERMINAL DISCONTINUOUS DISTURBANCE VOLTAGE/CLICK	
4.1 Block Diagram of Test Setup	^
4.1 BLOCK DIAGRAM OF TEST SETUP	
4.2 TEST SETOP AND TEST PROCEEDORE	
5. CONTINUOUS DISTURBANCE POWER 22	
5.1 CONTINUOUS DISTURBANCE POWER LIMIT	
5.2 BLOCK DIAGRAM OF TEST SET UP	
5.3 Test Procedure	
5.4 Test Protocol	3
6. RADIATED EMISSION	5
6.1 LIMIT	5
6.2 Block diagram and test set up	5
6.3 Test Protocol	6
7. HARMONICS	8
7.1 Block Diagram of Test Setup	8
7.2 TEST SETUP AND TEST PROCEDURE	
7.3 Test Protocol	8
8. VOLTAGE FLUCTUATIONS-FLICKER	9
8.1 Block Diagram of Test Setup	q
8.2 TEST SETUP AND TEST PROCEDURE	
8.2.1 Definition	
8.2.2 Test condition	
8.3 TEST PROTOCOL	-
	-
IMMUNITY TEST	1

intertek

Total Quality. Assured.

9.1 SEVERTY LEVEL AND PERFORMANCE CRITERION. 32 9.1.1 Test Performance Criterion 32 9.2 BLOCK DIAGRAM OF TEST SETUP. 33 9.3 TEST SETUP AND TEST PROCEDURE. 34 9.4 TEST PROTOCOL. 35 10.6 ELECTROMAGNETIC FIELD SUSCEPTIBILITY. 36 10.1 SEVERTY LEVEL AND PERFORMANCE CRITERION. 36 10.1.1 Test Performance Criterion 36 10.2 BLOCK DIAGRAM OF TEST SETUP. 37 10.4 TEST PROTOCOL. 37 11.4 ELECTRIC FAST TRANSIENT/BURST IMMUNITY TEST 38 11.1 SEVERTY LEVEL AND PERFORMANCE CRITERION. 38 11.1 Test Performance Criterion 38 11.1 Test Performance Criterion 38 11.1 Test Performance Criterion 38 11.1.1 Test Performance Criterion 38 11.1.2 Performance Criterion 38 11.1.1 Test Performance Criterion 39 11.2.1 Block Diagram for input a.c./d.c. power line 39 11.3.1 Test SETUP AND TEST PROCEDURE	9.	ELECTROSTATIC DISCHARGE (ESD)	32
9.1.2 Performance Criterion 32 9.2 BLOCK DUAGRAM OF TEST STUP 33 9.3 TEST PROCEDURE 34 9.4 TEST PROCEDURE 35 10. ELECTROMAGRETIC FIELD SUSCEPTIBILITY 36 10.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 36 10.1 Test Veril 36 10.1 Test Veril 36 10.2 Performance Criterion 36 10.1 Test Serue AND TEST PROCEDURE 37 10.3 TEST SERUE AND TEST PROCEDURE 37 10.4 TEST PROTOCOL 37 11. ELECTRIC FAST TRANSIENT/BURST IMMUNITY TEST 38 11.1 Test Performance Criterion 38 11.1 Test Serue AND PERFORMANCE CRITERION 38 11.2 Block Diagram for input a.c./d.c. power line or signal/control lines. 40 11.3 TEST SETUE NOT EST SETUP 39 11.2.2 Block Diagram for input a.c./d.c. power line or signal/control lines. 40 11.4 TEST SETUP NOT EST SETUP 39 11.2.2 Block Diagram for input a.c./d.c. power line or signal	9.1	Severity Level and Performance Criterion	32
9.2 BLOCK DIAGRAM OF TEST SETUP 33 9.4 TEST SETUP AND TEST PROCEDURE 34 9.4 TEST PROTOCOL 35 10. ELECTROMAGNETIC FIELD SUSCEPTIBILITY 36 10.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 36 10.1.1 Test I evel 36 10.1.2 Performance Criterion 36 10.1.3 TEST SETUP AND TEST PROCEDURE 37 10.4 TEST PROTOCOL 37 10.5 TEST PROTOCOL 37 11. ELECTRIC FAST TRANSIENT/BURST IMMUNITY TEST 38 11.1 TEST PROTOCOL 37 11.4 ELECTRIC FAST TRANSIENT/BURST IMMUNITY TEST 38 11.1 TEST PROTOCOL 37 11.5 EVERTIV LEVEL AND PERFORMANCE CRITERION 38 11.1.1 TEST SETUP 38 11.2 BLOCK DIAGRAM OF TEST SETUP 39 11.2.1 BLOCK DIAGRAM OF TEST SETUP 39 11.2.1 BLOCK DIAGRAM OF TEST SETUP 40 11.3 TEST DETUP AND TEST PROCEDURE 40 11.4 TEST PROCEDURE		9.1.1 Test level	
9.3 TEST SETUP AND TEST PROCEDURE 34 9.4 TEST PROTOCOL 35 10. ELECTROMAGNETIC FIELD SUSCEPTIBILITY 36 10.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 36 10.1.1 Test level 36 10.1.2 Performance Criterion 36 10.1.2 Performance Criterion 36 10.1.3 TEST SETUP AND TEST PROCEDURE 37 10.4 TEST PROTOCOL 37 11.4 TEST PROTOCOL 38 11.1 Test PROTOCOL 38 11.1 Test Performance Criterion 38 11.2.1 Block Diagram for input a. c./d.c. power line or signal/control lines. 40 11.2.1 Block Diagram for output a. c./d.c. power line or signal/control lines. 40 11.2.1 Block Diagram for output a. c./d.c. power line or signal/control lines. 40 11.2.1 Block Diagram for output a. c./d.c. power line or signal/control li		9.1.2 Performance Criterion	
9.4 TEST PROTOCOL 35 10. ELECTROMAGNETIC FIELD SUSCEPTIBILITY 36 10.1 SEVERTY LEVEL AND PERFORMANCE CRITERION 36 10.1.1 Test level 36 10.1.2 Performance Criterion 36 10.2 BLOCK DUAGRAM OF TEST SETUP 37 10.3 TEST SETUP AND TEST PROCEDURE 37 10.4 TEST PROTOCOL 37 11.5 EVERTY LEVEL AND PERFORMANCE CRITERION 38 11.1 Test VEVEL 38 11.1 Test VEVEL 38 11.1.1 Test VEVEL 38 11.1.2 Performance Criterion 38 11.2.1 Block Diagram for input a.c./d.c. power line or signal/control lines 40 11.3 TEST SETUP AND TEST SETUP 39 11.2.1 Block Diagram for output a.c./d.c. power line or signal/control lines 40 11.3 TEST SETUP AND TEST PROCEDURE 42 12.1 Block Diagram for output a.c./d.c. power line or signal/control lines 42 12.2 Block Diagram for output a.c./d.c. power line or signal/control lines 42 12.1	9.2	BLOCK DIAGRAM OF TEST SETUP	33
10. ELECTROMAGNETIC FIELD SUSCEPTIBILITY 36 10.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 36 10.1.1 Test level. 36 10.1.2 Performance Criterion 36 10.3 TEST SETUP AND TEST PROCEDURE 37 10.4 TEST PROTOCOL 37 10.4 TEST PROTOCOL 37 11.5 EVERITY LEVEL AND PERFORMANCE CRITERION 38 11.1 Test level. 38 11.2 BLOCK DIAGRAM OF TEST SETUP 38 11.2 BLOCK DIAGRAM OF TEST SETUP 39 11.2.1 BLOCK DIAGRAM OF TEST SETUP 40 11.3 TEST SETUP AND TEST PROCEDURE 40 11.4 TEST PROTOCOL 41 12.5 SURGE IMMUNITY TEST 42 12.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 42 12.1 TEST EVEND AND TEST PROCEDURE 43 13.1 IMMUNITY TOC CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQ	9.3	TEST SETUP AND TEST PROCEDURE	34
10.1 SEVERTY LEVEL AND PERFORMANCE CRITERION. 36 10.1.1 Test level. 36 10.2 BLOCK DIAGRAM OT EST SETUP 37 10.3 TEST SETUP AND TEST PROCEDURE 37 10.4 TEST PROTOCOL 37 10.4 TEST PROTOCOL 37 11. ELECTRIC FAST TRANSIENT/BURST IMMUNITY TEST 38 11.1 Test level 38 11.1 Test level 38 11.1 Test level 38 11.1.2 Performance Criterion 38 11.2.1 Block Diagram for input a.c./d.c. power line. 39 11.2.2 Block Diagram for input a.c./d.c. power line or signal/control lines. 40 11.3 TEST SETUP AND TEST PROCEDURE 41 12.1 Block Diagram for input a.c./d.c. power line or signal/control lines. 40 11.3 TEST SETUP AND TEST PROCEDURE 42 12.1 Seventry Level AND PERFORMANCE CRITERION. 42 12.1 Seventry Level AND PERFORMANCE CRITERION. 42 12.1 Seventry Level AND PERFORMANCE CRITERION. 42 12.1.2 Block Din	9.4	TEST PROTOCOL	35
10.1 SEVERTY LEVEL AND PERFORMANCE CRITERION. 36 10.1.1 Test level. 36 10.2 BLOCK DIAGRAM OT EST SETUP 37 10.3 TEST SETUP AND TEST PROCEDURE 37 10.4 TEST PROTOCOL 37 10.4 TEST PROTOCOL 37 11. ELECTRIC FAST TRANSIENT/BURST IMMUNITY TEST 38 11.1 Test level 38 11.1 Test level 38 11.1 Test level 38 11.1.2 Performance Criterion 38 11.2.1 Block Diagram for input a.c./d.c. power line. 39 11.2.2 Block Diagram for input a.c./d.c. power line or signal/control lines. 40 11.3 TEST SETUP AND TEST PROCEDURE 41 12.1 Block Diagram for input a.c./d.c. power line or signal/control lines. 40 11.3 TEST SETUP AND TEST PROCEDURE 42 12.1 Seventry Level AND PERFORMANCE CRITERION. 42 12.1 Seventry Level AND PERFORMANCE CRITERION. 42 12.1 Seventry Level AND PERFORMANCE CRITERION. 42 12.1.2 Block Din	10.	ELECTROMAGNETIC FIELD SUSCEPTIBILITY	
10.1.1 Test level			
10.1.2 Performance Criterion 36 10.2 BLOCK DIAGRAM OT TEST SETUP 37 10.3 TEST SETUP AND TEST PROCEDURE 37 10.4 TEST SETUP AND TEST PROCEDURE 37 11. ELECTRIC FAST TRANSIENT/BURST IMMUNITY TEST 38 11.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 38 11.1 Test level. 38 11.1 Test level. 38 11.2 Performance Criterion 38 11.2.1 BLOCK DIAGRAM OF TEST SETUP 39 11.2.2 BLOCK DIAGRAM OF TEST SETUP 39 11.2.1 BLOCK DIAGRAM OF TEST SETUP 39 11.2.2 BLOCK DIAGRAM OF TEST SETUP 39 11.2.1 BLOCK DIAGRAM OF TEST PROCEDURE 40 11.4 TEST PROTOCOL 41 12.2 BLOCK DIAGRAM OF TEST SETUP 42 12.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 42 12.1 TEST FUP AND TEST PROCEDURE 42 12.2 BLOCK DIAGRAM OT TEST SETUP 43 12.3 TEST SETUP AND TEST PROCEDURE 43 12.4	-		
10.2 BLOCK DIAGRAM OF TEST SETUP 37 10.3 TEST SETUP AND TEST PROCEDURE 37 10.4 TEST PROTOCOL 37 11. ELECTRIC FAST TRANSIENT/BURST IMMUNITY TEST 38 11.1 TEST EVEL AND PERFORMANCE CRITERION 38 11.1 Test level 38 11.1 Test level 38 11.1 Test level 38 11.1 Test level 39 11.2 Block Diagram for input a.c./d.c. power line 39 11.2.1 Block Diagram for output a.c./d.c. power line 39 11.2 Test Setup AND TEST PROCEDURE 40 11.3 TEST Setup AND TEST PROCEDURE 40 11.4 TEST PROTOCOL 41 12 SURGE IMMUNITY TEST. 42 12.1.1 Test PROTOCOL 41 12 SURGE IMMUNITY TEST 42 12.1.1 Test PROTOCOL 42 12.2 BLOCK DIAGRAM OF TEST SETUP 43 12.3 TEST FORTOCOL 43 13.4 TEST PROTOCOL 43 13.1			
10.3 TEST SETUP AND TEST PROCEDURE 37 10.4 TEST PROTOCOL 37 11. ELECTRIC FAST TRANSIENT/BURST IMMUNITY TEST 38 11.1 SEVERTY LEVEL AND PERFORMANCE CRITERION 38 11.1.2 Performance Criterion 38 11.2 Performance Criterion 38 11.2 Block Diagram for input a.c./d.c. power line 39 11.2.1 Block Diagram for output a.c./d.c. power line 39 11.2.2 Block Diagram for output a.c./d.c. power line 40 11.3 TEST SETUP AND TEST PROCEDURE 40 11.4 TEST PROTOCOL 41 12. SURGE IMMUNITY TEST 42 12.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 42 12.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 42 12.1 TEST FERUP 43 12.2 BLOCK DIAGRAM OF TEST SETUP 43 12.3 TEST PROTOCOL 43 12.4 TEST PROTOCOL 43 13.1 TEST PROTOCOL 43 13.1 TEST PROTOCOL 43 13.1 T			
10.4 TEST PROTOCOL 37 11. ELECTRIC FAST TRANSIENT/BURST IMMUNITY TEST 38 11.1 Test level 38 11.1 Test level 38 11.1.1 Test level 38 11.1.2 Performance Criterion 38 11.1.1 Block Diagram for input a.c./d.c. power line 39 11.2.1 Block Diagram for output a.c./d.c. power line 39 11.2.1 Block Diagram for output a.c./d.c. power line 39 11.3 TEST SETUP AND TEST PROCEDURE 40 11.4 TEST PROTOCOL 41 12 SURGE IMMUNITY TEST 42 12.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 42 12.1.1 Test level 42 12.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 42 12.1.2 Performance Criterion 42 12.1.1 Test level 42 12.1.2 Performance Criterion 42 12.1.1 Test PROTOCOL 43 12.2 BLOCK DLAGRAM OF TEST SETUP 43 13.3 TEST PROTOCOL 44	-		
11. ELECTRIC FAST TRANSIENT/BURST IMMUNITY TEST 38 11.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 38 11.1.1 Test level. 38 11.1.2 Performance Criterion 38 11.1.1 Test level. 38 11.1.2 Derformance Criterion 38 11.2 Block Diagram for input a.c./d.c. power line 39 11.2.1 Block Diagram for output a.c./d.c. power line or signal/control lines 40 11.3 TEST SETUP AND TEST PROCEDURE 40 11.4 TEST PROTOCOL 41 12. SURGE IMMUNITY TEST 42 12.1 Seventry Level AND Performance Criterion 42 12.1 Test level. 42 12.2 Block Diagram or EST SETUP 43 12.1 Test level. 42 12.2 Performance Criterion 42 12.2 Performance Criterion 43 12.3 TEST SETUP AND TEST PROCEDURE 43 13.1 TEST SETUP AND TEST PROCEDURE 44 13.1 TEST SETUP AND TEST PROCEDURE <t< td=""><td></td><td></td><td></td></t<>			
11.1 SEVERITY LEVEL AND PERFORMANCE CRITERION			
11.1.1 Test level.	11.	ELECTRIC FAST TRANSIENT/BURST IMMUNITY TEST	38
11.1.2 Performance Criterion 38 11.2 BLOCK DIAGRAM OF TEST SETUP 39 11.2.1 Block Diagram for input a.c./d.c. power line 39 11.2.2 Block Diagram for output a.c./d.c. power line or signal/control lines 40 11.3 TEST SETUP AND TEST PROCEDURE 40 11.4 TEST PROTOCOL 41 12. SURGE IMMUNITY TEST 42 12.1 SEVENTY LEVEL AND PERFORMANCE CRITERION 42 12.1.1 Test Setup 43 12.1 Performance Criterion 42 12.1.2 Performance Criterion 42 12.1.3 Test Setup AND TEST PROCEDURE 43 12.3 TEST SETUP AND TEST PROCEDURE 43 12.4 TEST PROTOCOL 43 13.1 IMMUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS. 44 13.1.1 Test Setup 44 13.1.2 Performance Criterion 44 13.1.1 Test Setup AND TEST PROCEDURE 44 13.2.2 Performance Criterion 44 13.1.1 Test Setup AND TEST PROCEDURE 44			
11.2 BLOCK DIAGRAM OF TEST SETUP 39 11.2.1 Block Diagram for input a.c./d.c. power line 39 11.2.2 Block Diagram for output a.c./d.c. power line or signal/control lines 40 11.3 TEST SETUP AND TEST PROCEDURE 40 11.4 TEST PROTOCOL 41 12. SURGE IMMUNITY TEST 42 12.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 42 12.1.1 Test level 42 12.1.2 Performance Criterion 42 12.1.3 TEST SETUP AND TEST PROCEDURE 43 12.4 TEST SETUP AND TEST PROCEDURE 43 12.3 TEST SETUP AND TEST PROCEDURE 43 12.4 TEST PROTOCOL 43 13.1 IMMUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS. 44 13.1 Test Performance Criterion 44 13.1.4 Test Performance Criterion 44 13.1.2 Performance Criterion 44 13.1.2 Performance Criterion 44 13.2.1 Performance Criterion 44 13.2.2 Performance Criterion			
11.2.1 Block Diagram for input a.c./d.c. power line 39 11.2.2 Block Diagram for output a.c./d.c. power line or signal/control lines 40 11.3 TEST SETUP AND TEST PROCEDURE 40 11.4 TEST PROTOCOL 41 12. SURGE IMMUNITY TEST 42 12.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 42 12.1.1 Test level 42 12.1.2 Performance Criterion 42 12.1.3 Test SETUP AND TEST SETUP 43 12.1 Performance Criterion 43 12.3 TEST SETUP AND TEST PROCEDURE 43 12.4 TEST PROTOCOL 43 13.1 IMMUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS 44 13.1 Test level 44 13.1 Test level 44 13.1.2 Performance Criterion 44 13.1.2 Performance Criterion 44 13.1.1 Test level 44 13.2 BLOCK DIAGRAM OF TEST SETUP 44 13.3 TEST SETUP AND TEST PROCEDURE 45 13.4		11.1.2 Performance Criterion	38
11.2.2 Block Diagram for output a.c./d.c. power line or signal/control lines	11.	2 BLOCK DIAGRAM OF TEST SETUP	39
11.3 TEST SETUP AND TEST PROCEDURE 40 11.4 TEST PROTOCOL 41 12. SURGE IMMUNITY TEST 42 12.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 42 12.1.1 Test level 42 12.1.2 Performance Criterion 42 12.2 BLOCK DIAGRAM OF TEST SETUP 43 12.3 TEST SETUP AND TEST PROCEDURE 43 12.4 TEST PROTOCOL 43 13.1 IMMUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS 44 13.1.1 Test level 44 13.1.2 Performance Criterion 44 13.1.1 Test level 44 13.1.2 Performance Criterion 44 13.1.1 Test level 44 13.1.2 Performance Criterion 44 13.1.3 Test level 44 13.1.4 Test level 44 13.1.1 Test level 44 13.1.2 Performance Criterion 44 13.1.1 Test level 44 13.2 BLOCK DIAGRAM		11.2.1 Block Diagram for input a.c./d.c. power line	
11.4 TEST PROTOCOL 41 12. SURGE IMMUNITY TEST 42 12.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 42 12.1.1 Test level 42 12.1.2 Performance Criterion 42 12.1.2 BLOCK DIAGRAM OF TEST SETUP 43 12.3 TEST SETUP AND TEST SETUP 43 12.4 TEST PROTOCOL 43 13. IMMUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS 44 13.1 TEST level 44 13.1.1 Test level 44 13.1.2 Performance Criterion 44 13.1.1 Test level 44 13.1.2 Performance Criterion 44 13.1.2 Performance Criterion 44 13.2 BLOCK DIAGRAM OF TEST SETUP 44 13.3 TEST SETUP AND TEST PROCEDURE 45 13.4 TEST PROTOCOL 46 14.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 47 14.1 TEST PROTOCOL 47 14.1.1 Test level 47 14.1		11.2.2 Block Diagram for output a.c./d.c. power line or signal/control lines	40
12. SURGE IMMUNITY TEST	11.	3 TEST SETUP AND TEST PROCEDURE	40
12.1 Severity Level and Performance Criterion 42 12.1.1 Test level. 42 12.1.2 Performance Criterion 42 12.2 BLOCK DIAGRAM OF TEST SETUP 43 12.3 TEST SETUP AND TEST PROCEDURE 43 12.4 TEST PROTOCOL 43 13.1 IMMUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS. 44 13.1 Severity Level and Performance Criterion 44 13.1.1 Test level. 44 13.1.2 Performance Criterion 44 13.1.2 Performance Criterion 44 13.2 BLOCK DIAGRAM OF TEST SETUP 44 13.1 Test level. 44 13.2 BLOCK DIAGRAM OF TEST SETUP 44 13.3 TEST SETUP AND TEST PROCEDURE 44 13.4 TEST PROTOCOL 45 13.4 TEST PROTOCOL 46 14.1 Severity Level and PERFORMANCE CRITERION 47 14.1 Test level. 47 14.1.1 Test level. 47 14.2 BLOCK DIAGRAM OF TEST SETUP	11.	4 TEST PROTOCOL	41
12.1.1 Test level 42 12.1.2 Performance Criterion 42 12.2 BLOCK DIAGRAM OF TEST SETUP 43 12.3 TEST SETUP AND TEST PROCEDURE 43 12.4 TEST PROTOCOL 43 13.1 IMMUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS 44 13.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 44 13.1.1 Test level. 44 13.1.2 Performance Criterion 44 13.2 BLOCK DIAGRAM OF TEST SETUP 44 13.3 TEST SETUP AND TEST PROCEDURE 44 13.4 TEST SETUP 44 13.5 BLOCK DIAGRAM OF TEST SETUP 44 13.6 TEST SETUP AND TEST PROCEDURE 45 13.4 TEST PROTOCOL 46 14. VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST 47 14.1 Test level 47 14.1 Test level 47 14.1 Test level 47 14.2 BLOCK DIAGRAM OF TEST SETUP 48 14.3 TEST SETUP AND TEST PROCE	12.	SURGE IMMUNITY TEST	42
12.1.1 Test level 42 12.1.2 Performance Criterion 42 12.2 BLOCK DIAGRAM OF TEST SETUP 43 12.3 TEST SETUP AND TEST PROCEDURE 43 12.4 TEST PROTOCOL 43 13.1 IMMUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS 44 13.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 44 13.1.1 Test level. 44 13.1.2 Performance Criterion 44 13.2 BLOCK DIAGRAM OF TEST SETUP 44 13.3 TEST SETUP AND TEST PROCEDURE 44 13.4 TEST SETUP 44 13.5 BLOCK DIAGRAM OF TEST SETUP 44 13.6 TEST SETUP AND TEST PROCEDURE 45 13.4 TEST PROTOCOL 46 14. VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST 47 14.1 Test level 47 14.1 Test level 47 14.1.1 Test level 47 14.2 BLOCK DIAGRAM OF TEST SETUP 48 14.3 TEST SETUP AND TEST PRO	12		42
12.1.2 Performance Criterion 42 12.2 BLOCK DIAGRAM OF TEST SETUP 43 12.3 TEST SETUP AND TEST PROCEDURE 43 12.4 TEST PROTOCOL 43 13. IMMUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS. 44 13.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 44 13.1.2 Performance Criterion 44 13.2 BLOCK DIAGRAM OF TEST SETUP 44 13.2 BLOCK DIAGRAM OF TEST SETUP 44 13.3 TEST SETUP AND TEST PROCEDURE 44 13.4 TEST SETUP AND TEST PROCEDURE 45 13.4 TEST PROTOCOL 46 14.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 47 14.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 47 14.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 47 14.1 TEST PROTOCOL 47 14.1 TEST NUMBER CRITERION 47 14.1 TEST PROTEOR 47 14.2 BLOCK DIAGRAM OF TEST SETUP 48 14.3 TEST SETUP AND TEST PROCEDURE 48			
12.2 BLOCK DIAGRAM OF TEST SETUP 43 12.3 TEST SETUP AND TEST PROCEDURE 43 12.4 TEST PROTOCOL 43 13. IMMUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS. 44 13.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 44 13.1.1 Test level. 44 13.1.2 Performance Criterion 44 13.2 BLOCK DIAGRAM OF TEST SETUP 44 13.3 TEST SETUP AND TEST PROCEDURE 44 13.4 TEST SETUP AND TEST PROCEDURE 45 13.4 TEST PROTOCOL 46 14.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 47 14.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 47 14.1 Test level. 47 14.1 Test level. 47 14.1.1 Test level. 47 14.2 Performance Criterion 47 14.2 Performance Criterion 47 14.3 TEST SETUP 48 14.3 TEST SETUP 48 14.3 TEST SETUP AND TEST PROCEDURE 4			
12.3 TEST SETUP AND TEST PROCEDURE 43 12.4 TEST PROTOCOL 43 13. IMMUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS. 44 13.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 44 13.1.1 Test level. 44 13.2 Performance Criterion 44 13.2 Performance Criterion 44 13.3 TEST SETUP 44 13.4 DEOCK DIAGRAM OF TEST SETUP 44 13.3 TEST SETUP AND TEST PROCEDURE 45 13.4 TEST PROTOCOL 46 14.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 47 14.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 47 14.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 47 14.1 Test level. 47 14.1.1 Test level. 47 14.2 Performance Criterion 47 14.2 BLOCK DIAGRAM OF TEST SETUP 48 14.3 TEST SETUP AND TEST PROCEDURE 48 14.4 TEST PROTOCOL 48		•	
12.4 TEST PROTOCOL 43 13. IMMUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS. 44 13.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 44 13.1.1 Test level. 44 13.2 Performance Criterion 44 13.3 TEST SETUP 44 13.4 TEST SETUP AND TEST SETUP 44 13.3 TEST SETUP AND TEST PROCEDURE 45 13.4 TEST PROTOCOL 46 14.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 47 14.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 47 14.1 Test level. 47 14.1.1 Test level. 47 14.1.2 Performance Criterion 47 14.2 BLOCK DIAGRAM OF TEST SETUP 48 14.3 TEST SETUP AND TEST PROCEDURE 48 14.4 TEST PERFORMANCE CRITERION 47 14.1.2 Performance Criterion 47 14.2 BLOCK DIAGRAM OF TEST SETUP 48 14.3 TEST SETUP AND TEST PROCEDURE 48 14.4 TEST PROTOCOL<			
13. IMMUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS. 44 13.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 44 13.1.1 Test level. 44 13.1.2 Performance Criterion 44 13.2 BLOCK DIAGRAM OF TEST SETUP 44 13.3 TEST SETUP AND TEST PROCEDURE 45 13.4 TEST PROTOCOL 46 14. VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST 47 14.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 47 14.1.1 Test level. 47 14.1.2 Performance Criterion 47 14.2 BLOCK DIAGRAM OF TEST SETUP 48 14.3 TEST SETUP AND TEST PROCEDURE 47 14.1.1 Test level. 47 14.2 BLOCK DIAGRAM OF TEST SETUP 48 14.3 TEST SETUP AND TEST PROCEDURE 48 14.4 TEST SETUP AND TEST PROCEDURE 48			
13.1 Severity Level and Performance Criterion 44 13.1.1 Test level 44 13.1.2 Performance Criterion 44 13.2 BLOCK DIAGRAM OF TEST SETUP 44 13.3 TEST SETUP AND TEST PROCEDURE 45 13.4 TEST PROTOCOL 46 14. VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST 47 14.1 Severity Level and Performance Criterion 47 14.1 Severity Level and Performance Criterion 47 14.1.1 Test level 47 14.1.2 Performance Criterion 47 14.2 BLOCK DIAGRAM OF TEST SETUP 48 14.3 TEST SETUP AND TEST PROCEDURE 48 14.4 TEST PROTOCOL 48			
13.1.1 Test level			
13.1.2 Performance Criterion 44 13.2 BLOCK DIAGRAM OF TEST SETUP 44 13.3 TEST SETUP AND TEST PROCEDURE 45 13.4 TEST PROTOCOL 46 14. VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST 47 14.1 Severity Level and Performance Criterion 47 14.1.1 Test level 47 14.2 Performance Criterion 47 14.3 TEST SETUP 48 14.3 TEST SETUP AND TEST PROCEDURE 48	13.		
13.2 BLOCK DIAGRAM OF TEST SETUP 44 13.3 TEST SETUP AND TEST PROCEDURE 45 13.4 TEST PROTOCOL 46 14. VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST 47 14.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 47 14.1.1 Test level 47 14.2 Performance Criterion 47 14.2 BLOCK DIAGRAM OF TEST SETUP 48 14.3 TEST SETUP AND TEST PROCEDURE 48 14.4 TEST PROTOCOL 48			
13.3 TEST SETUP AND TEST PROCEDURE 45 13.4 TEST PROTOCOL 46 14. VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST 47 14.1 SEVERITY LEVEL AND PERFORMANCE CRITERION 47 14.1.1 Test level 47 14.1.2 Performance Criterion 47 14.2 BLOCK DIAGRAM OF TEST SETUP 48 14.3 TEST SETUP AND TEST PROCEDURE 48 14.4 TEST PROTOCOL 48		-	
13.4 TEST PROTOCOL	-		
14. VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST 47 14.1 Severity Level and Performance Criterion 47 14.1.1 Test level 47 14.1.2 Performance Criterion 47 14.2 Block DIAGRAM OF TEST SETUP 48 14.3 TEST SETUP AND TEST PROCEDURE 48 14.4 TEST PROTOCOL 48	-		
14.1 Severity Level and Performance Criterion 47 14.1.1 Test level 47 14.1.2 Performance Criterion 47 14.2 Block diagram of test setup 48 14.3 Test Setup and Test Procedure 48 14.4 Test Protocol 48	13.	4 TEST PROTOCOL	46
14.1.1 Test level	14.	VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST	47
14.1.2Performance Criterion4714.2BLOCK DIAGRAM OF TEST SETUP4814.3TEST SETUP AND TEST PROCEDURE4814.4TEST PROTOCOL48	14.	1 Severity Level and Performance Criterion	47
14.2BLOCK DIAGRAM OF TEST SETUP4814.3TEST SETUP AND TEST PROCEDURE4814.4TEST PROTOCOL48		14.1.1 Test level	47
14.2BLOCK DIAGRAM OF TEST SETUP4814.3TEST SETUP AND TEST PROCEDURE4814.4TEST PROTOCOL48		14.1.2 Performance Criterion	47
14.3 Test Setup and Test Procedure	14.		
14.4 Test Protocol	14.		
	14.	4 TEST PROTOCOL	48



Revision History

Report No.	Version	Description	Issued Date
191102430SHA-001	Rev. 01	Initial issue of report	December 4, 2019



Measurement result summary

TEST ITEM	TEST RESULT	NOTE
Mains terminal continuous disturbance voltage	Pass	
Mains terminal discontinuous disturbance voltage/click	NA	
Continuous disturbance power	Pass	
Radiated Emission	Pass	
Harmonics	Pass	
Voltage fluctuation-Flicker	Pass	
Electrostatic Discharge (ESD)	Pass	
RF electromagnetic field susceptibility	Pass	
Electric Fast Transient /Burst (EFT/B)	Pass	
Surge	Pass	
Injected Current	Pass	
Voltage dips and interruption	Pass	

Notes:

- 1. NA =Not Applicable
- 2. Determination of the test conclusion is based on IEC Guide 115 in consideration of measurement uncertainty.
- 3. Additions, Deviations and Exclusions from Standards: None.

intertek

Total Quality. Assured.

1. GENERAL INFORMATION

1.1 Description of Equipment Under Test (EUT)

Product name	:	Children's Car.
Type/Model	:	JE1001
Brand name	:	-
Description of EUT	:	This report is based on the report 190602440SHA-001 dated on June July 22, 2019 issued by Intertek Testing Services Shanghai. Updated the model information. All the models are similar with each other except the model names and appearance. Tested the model with the Charger:LK-D060050. The worst data has been listed as representative.
Rating	:	Battery: 6Vd.c. Battery charger: Input: 230-240VAC~, 50Hz, 8W Output: 6VDC, 0.5A
Highest operating frequency	:	<108MHz
EUT type	:	☐ Table-top ⊠ Floor standing
EUT is toy, defined as		 Category A Category B Category C Category D Category E
Sample received date	:	June 25, 2019
Sample identification No.	:	0190625-25
Date of test	:	June 25, 2019~July 15, 2019



1.2 Description of Test Facility

Name	:	Intertek Testing Services Shanghai
Address	:	Building 86, No. 1198 Qinzhou Road(North), Shanghai 200233, P.R. China
•		86 21 61278200 86 21 54262353
The test facility is recognized, certified, or accredited by these organizations	:	CNAS Accreditation Lab Registration No. CNAS L0139 FCC Accredited Lab Designation Number: CN1175 IC Registration Lab CAB identifier.: CN0051 VCCI Registration Lab Registration No.: R-14243, G-10845, C-14723, T-12252 A2LA Accreditation Lab Certificate Number: 3309.02

ntertek

2. TEST SPECIFICATIONS

2.1 Normative Standards

IEC 61000-4-2:2008: Electromagnetic Compatibility (EMC) - Part 4-2: testing and measurement techniques - electrostatic discharge immunity test

IEC 61000-4-3:2006+A1:2007+A1:2010: Electromagnetic Compatibility (EMC) - Part 4-3: testing and measurement techniques - radiated, radio frequency, electromagnetic field immunity test

IEC 61000-4-4:2012: Electromagnetic Compatibility (EMC) - Part 4-4: testing and measurement techniques - electric fast transient/burst immunity test

IEC 61000-4-5:2014: Electromagnetic Compatibility (EMC) - Part 4-5: testing and measurement techniques - section 5: surge immunity test

IEC 61000-4-6:2013: Electromagnetic Compatibility (EMC) - Part 4-6: testing and measurement techniques - section 6: immunity to conducted disturbance, induced by radio frequency field

IEC 61000-4-11:2004: Electromagnetic Compatibility (EMC) - Part 4-11: testing and measurement techniques -voltage dips, short interruption and voltage variations immunity test

IEC 61000-4-22:2010, Electromagnetic compatibility (EMC) - Part 4-22: Testing and measurement techniques – Radiated emissions and immunity measurements in fully anechoic rooms (FARs)

Note: there are no magnetic sensitive components included in this EUT and magnetic field immunity test according to EN 61000-4-8 is therefore not required.

intertek Total Quality. Assured.

2.2 Mode of operation during the test

Within this test report, EUT was tested under all available operation modes and tested under its rating voltage and frequency. Other voltage and frequency is specified if used.

2.3 Test Peripherals used

Item No	Description	Band and Model	S/No
1	-	-	-

2.4 Record of climatic conditions

Test Item	Temperature (°C)	Relative Humidity (%)	Pressure (Kpa)
Mains terminal continuous disturbance voltage	24	48	101
Mains terminal discontinuous disturbance voltage/click	NA	NA	NA
Continuous disturbance power	24	48	101
Radiated Emission	27	52	101
Harmonics	NA	NA	NA
Voltage fluctuation-Flicker	NA	NA	NA
Electrostatic Discharge (ESD)	26	55	101
RF electromagnetic field susceptibility	27	52	101
Electric Fast Transient /Burst (EFT/B)	26	55	101
Surge	26	55	101
Injected Current	22	49	101
Voltage dips and interruption	26	55	101

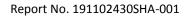
Notes: NA =Not Applicable

intertek

Total Quality. Assured.

2.5 Instrument list

Condu	Conducted Emission / Disturbance Power / Tri-loop Test / CDN method					
Used	Equipment	Manufacturer	Туре	Internal no.	Due date	
\boxtimes	Test Receiver	R&S	ESCS 30	EC 2107	2019-07-15	
\boxtimes	A.M.N.	R&S	ESH2-Z5	EC 3119	2019-11-29	
\boxtimes	Absorbing clamp	R&S	MDS 21	EC 2108	2020-06-13	
\boxtimes	Shielded room	Zhongyu	-	EC 2838	2020-01-13	
Radiate	ed Emission					
Used	Equipment	Manufacturer	Туре	Internal no.	Due date	
\boxtimes	Test Receiver	R&S	ESIB 26	EC 3045	2019-09-12	
\boxtimes	Bilog Antenna	TESEQ	CBL 6112D	EC 4206	2020-06-09	
\boxtimes	Semi-anechoic chamber	Albatross project	-	EC 3048	2019-07-31	
ESD						
Used	Equipment	Manufacturer	Туре	Internal no.	Due date	
\boxtimes	ESD generator	TESEQ	NSG 437	EC 4792-4	2020-03-27	
\boxtimes	Shielded room	Zhongyu	-	EC 2839	2020-01-13	
<mark>EFT / S</mark>	urge / Voltage Dips					
Used	Equipment	Manufacturer	Туре	Internal no.	Due date	
\boxtimes	Conduct immunity system	EM TEST	UCS 500M6B	EC 2958	2020-04-02	
\boxtimes	Automatic transformer	EM TEST	MV2616	EC 2957	2020-04-02	
\boxtimes	Shielded room	Zhongyu	-	EC 2839	2020-01-13	
Condu	cted Immunity			-		
Used	Equipment	Manufacturer	Туре	Internal no.	Due date	
\boxtimes	Signal generator	R&S	SML 01	EC 2338	2019-09-12	
\boxtimes	Power amplifier	AR	75A250	EC 3043-1	2019-07-15	
\boxtimes	Attenuator	EM TEST	ATT6/75	EC 3043-3	2020-02-11	
\boxtimes	CDN	Frankonia	CDN M2M316	EC 5969	2020-03-28	
Radiate	ed Immunity					
Used	Equipment	Manufacturer	Туре	Internal no.	Due date	
\boxtimes	Signal generator	R&S	SMR 20	EC 3044-1	2020-01-13	
\boxtimes	Power amplifier	AR	250W1000B	EC 5818-2	2020-04-14	
\boxtimes	Log-period antenna	AR	AT 1080	EC 3044-7	2020-03-04	
\boxtimes	Fully-anechoic chamber	Albatross project	-	EC 3047	2019-07-31	
Additic	onal instrument					
Used	Equipment	Manufacturer	Туре	Internal no.	Due date	
\boxtimes	Therom-	ZJ1-2A	S.M.I.F.	EC 3783	2020-03-10	



intertek

Total Quality. Assured.

	Hygrograph				
\boxtimes	Therom- Hygrograph	ZJ1-2A	S.M.I.F.	EC 2323	2020-06-06
\boxtimes	Therom- Hygrograph	ZJ1-2A	S.M.I.F.	EC 5198	2020-02-27
\boxtimes	Therom- Hygrograph	ZJ1-2A	S.M.I.F.	EC 3325	2020-04-07
\boxtimes	Pressure meter	YM3	Shanghai Mengde	EC 3320	2020-06-30



2.6 Measurement Uncertainty

Measurement	Frequency	Expanded Uncertainty (k=2) (±)
Conducted emission at mains nexts	9kHz ~ 150kHz	3.71 dB
Conducted emission at mains ports	150kHz ~ 30MHz	3.31 dB
Continuous disturbance voltage at telecom port with AAN	150kHz ~ 30MHz	4.10 dB
Continuous disturbance current at telecom ports	150kHz ~ 30MHz	2.73 dB
Mains terminal discontinuous disturbance voltage/click	-	3.87 dB
Continuous disturbance power	30MHz ~ 300MHz	4.42 dB
Radiated Emissions up to 1 GHz	30MHz ~ 1GHz	5.04 dB
Radiated Emissions above 1 GHz	1GHz ~ 6GHz	4.97 dB
Radiated Emissions above 1 GHz	6GHz ~ 18GHz	5.29 dB
Harmonic current emission	-	3.90%
Voltage fluctuations and flicker	-	10.34%
ESD	-	6.65%
Radiated susceptibility	-	2.38%
EFT test at main terminal	-	11.57%
EFT test at signal/telecom terminal	-	11.62%
Surge test at main terminal	-	11.57%
Injected current test at main terminal	-	1.88 dB
Injected current test at unshielded signal terminal	-	3.41 dB
Voltage dips and interruption	-	6.05%

Emission Test

3. Mains/Load/Control Terminal Continuous Disturbance Voltage

Test result: PASS

3.1 Terminal Voltage Limits for the frequency range 9kHz to 30MHz

3.1.1 General limits

	Mains	s ports	Associated ports			
Frequency range (MHz)	Disturban	ice voltage	Disturban	ce voltage	Disturban	ce current
(10112)	Limits	dB(μV)	Limits dB(µV)		Limits	dB(μV)
	Quasi-pea	k Average	Quasi-peak	Average	Quasi-peak	Average
0.15 ~ 0.5	66~56*	59 ~ 46 *	80	70	40 ~ 30 *	30 ~ 20 *
0.5 ~ 5.0	56	46	74	64	30	20
5.0 ~ 30	60	50	74	64	50	20
Notes:						

1. * means the limit decreasing linearly with the logarithm of the frequency in the range 0.15MHz to 0.5MHz.

2. If the quasi-peak measurements meet the average limit, the EUT shall be deemed to meet both limits and the measurements using the average detector need not be carried out.

3.1.2 Limits for mains port of tools

	P ≤ 700 W		700 W < P	≤ 1 000 W	P > 1 (000 W
Frequency range	Limits	dB(μV)	Limits	dB(μV)	Limits	dB(μV)
(MHz)	Quasi-pea	k Average	Quasi-peak	Average	Quasi-peak	Average
0.15-0.35	66-59*	59-49*	70-63*	63-53*	76-69*	69 ~ 59 *
0.35-5	59	49	63	53	69	59
5-30	64	54	68	58	74	64

Notes:

1. * means the limit decreasing linearly with the logarithm of the frequency in the range 0.15MHz to 0.35MHz.

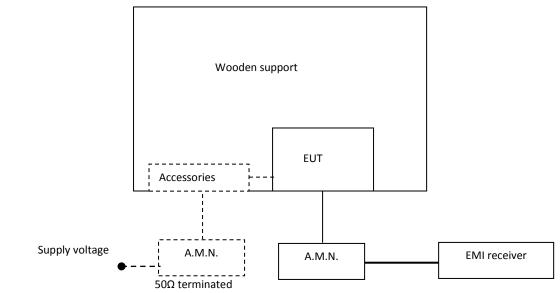
2. If the quasi-peak measurements meet the average limit, the EUT shall be deemed to meet both limits and the measurements using the average detector need not be carried out.



Total Quality. Assured.

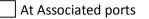
3.2 Block Diagram of Test Setup

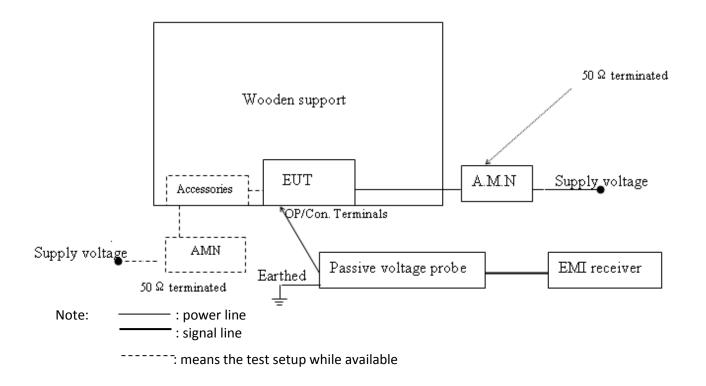
At mains terminal



For table top equipment, wooden support is 0.8m height table

For floor standing equipment, wooden support is 0.1m height rack.







Total Quality. Assured.

3.3 **Test Setup and Test Procedure**

Measurement was performed in shielded room, and instruments used were according to clause 5.1 of EN 55014-1 if applicable.

Detailed test procedure and arrangement was according to clause 5.2 of EN 55014-1.

Measurement methods was according to clause 5.4 of EN 55014-1.

Operation conditions of EUT was according to clause 6 of EN 55014-1.

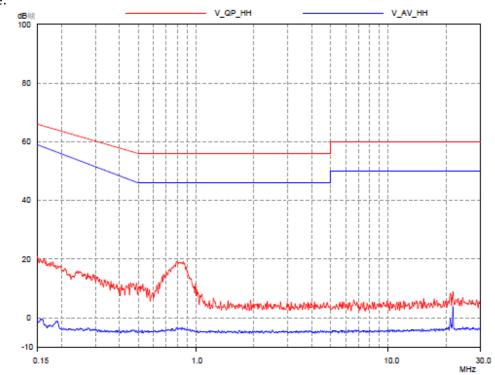
Frequency range 150kHz – 30MHz was checked and EMI receiver measurement bandwidth was set to 9kHz.



3.4 Test Protocol

For Mains ports: Pass

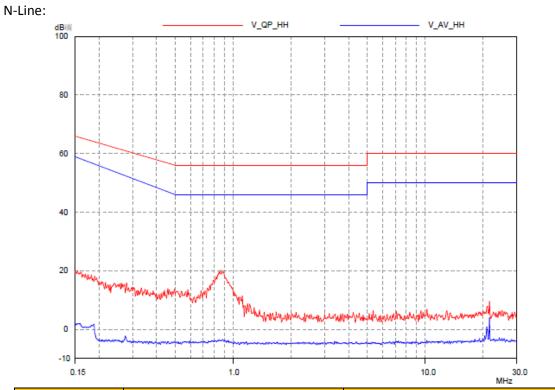
L-Line:



		Quasi-peak			Average	
Frequency (MHz)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)
0.34	*	59.10	*	*	50.03	*
0.36	*	58.64	*	*	49.43	*
0.37	*	58.44	*	*	49.17	*
0.61	*	56.00	*	*	46.00	*
0.83	*	56.00	*	*	46.00	*
1.36	*	56.00	*	*	46.00	*
Note: * means th	e emission le	evel 10dB bel	low the rele	vant limit.		

Total Quality. Assured.

itertek



		Quasi-peak			Average	
Frequency (MHz)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)
0.34	*	59.10	*	*	50.03	*
0.36	*	58.64	*	*	49.43	*
0.37	*	58.44	*	*	49.17	*
0.61	*	56.00	*	*	46.00	*
0.83	*	56.00	*	*	46.00	*
1.36	*	56.00	*	*	46.00	*
Note: * means th	e emission le	vel 10dB be	low the rele	vant limit		•

Note: ' means the emission level 10dB below the relevant limit.

Remark: 1. Correct Factor = LISN Factor + Cable Loss, the value was added to Original Receiver Reading by the software automatically.

2. Corrected Reading = Original Receiver Reading + Correct Factor

- 3. Margin = Limit Corrected Reading
- 4. If the PK Corrected Reading is lower than AV limit, the AV test can be elided.

Example: Assuming LISN Factor = 10.00dB, Cable Loss = 2.00dB,

Original Receiver Reading = 10.00dBuV, Limit = 66.00dBuV.

Then Correct Factor = 10.00 + 2.00 = 12.00dB;

Corrected Reading = 10dBuV + 12.00dB = 22.00dBuV;

Margin = 66.00dBuV - 22.00dBuV = 44.00dB.



For Associated ports: NA

		Quasi-peak			Average	
Frequency (MHz)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)
Note: * means th	e emission le	evel 20dB be	low the rele	vant limit.		

- Remark: 1. Correct Factor = LISN Factor + Cable Loss, the value was added to Original Receiver Reading by the software automatically.
 - 2. Corrected Reading = Original Receiver Reading + Correct Factor
 - 3. Margin = Limit Corrected Reading
 - 4. If the PK Corrected Reading is lower than AV limit, the AV test can be elided.

Example: Assuming LISN Factor = 10.00dB, Cable Loss = 2.00dB,

Original Receiver Reading = 10.00dBuV, Limit = 66.00dBuV.

Then Correct Factor = 10.00 + 2.00 = 12.00dB;

Corrected Reading = 10dBuV + 12.00dB = 22.00dBuV;

Margin = 66.00dBuV - 22.00dBuV = 44.00dB.

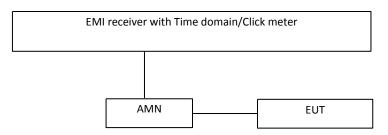
ntertek

Total Quality. Assured.

Mains terminal discontinuous disturbance voltage/click 4.

Test result: NA

4.1 **Block Diagram of Test Setup**



4.2 **Test Setup and Test Procedure**

Measurement was performed in shielded room, and instruments used were according to clause 5.1 of EN 55014-1 if applicable.

Detailed test procedure and arrangement was according to clause 5.2 of EN 55014-1.

Measurement methods was according to clause 5.4 of EN 55014-1.

Operation conditions of EUT was according to clause 6 of EN 55014-1.

0.15MHz, 0.5MHz, 1.4MHz and 30MHz were spot checked, and upper quartile methods used during measurement.

The final judgment of test result was according to figure 6 of EN 55014-1.



4.3 Test Protocol

Frequency				
(MHz)	0.15	0.5	1.4	30.0
Permitted limit				
for continuous interference	66.0	56.0	56.0	60.0
(dBµV)				
Counted click/switch operation				
number				
Observed time (min)				
Click duration (ms)				
Click rate N				
Factor				
Permitted limits for clicks (dBµv)				
Counted clicks exceeding the				
limits				
Test result				
Any other descriptions:				

intertek

Total Quality. Assured.

5. Continuous disturbance power

Test result:

5.1 Continuous disturbance power limit

Pass

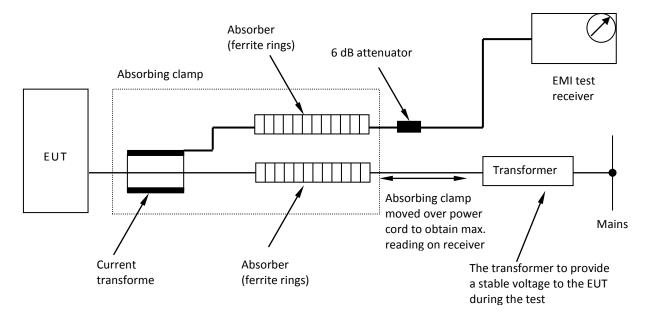
	Gene	eral	P ≤ 1	700 W	700 W < P ≤	≤ 1 000 W	P > 1 0	00 W
Frequency range	Limits c	lB(μV)	Limits	dB(μV)	Limits c	lB(μV)	Limits d	lB(μV)
(MHz)	Quasi-peak	Average	Quasi-pea	k Average	Quasi-peak	Average	Quasi-peak	Average
30-300	45-55*	35-45*	45-55*	35-45*	49-59*	39-49*	55-65*	45 55*
Notoci								

Notes:

1. * means the limit decreasing linearly with the logarithm of the frequency in the range 30MHz to 300MHz.

2. If the quasi-peak measurements meet the average limit, the EUT shall be deemed to meet both limits and the measurements using the average detector need not be carried out.

5.2 Block diagram of test set up



5.3 Test Procedure

Measurement was performed in shielded room, and instruments used were according to clause 5.1 of EN 55014-1 if applicable.

Detailed test procedure and arrangement was according to clause 5.3 of EN 55014-1.

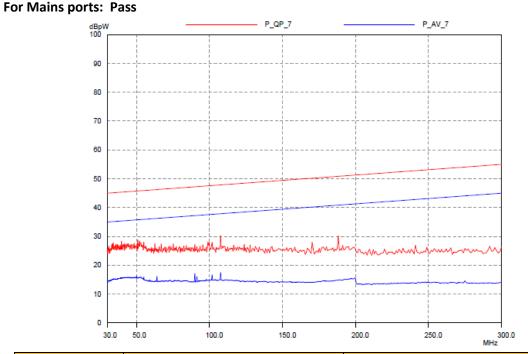
Measurement methods was according to clause 5.4 of EN 55014-1.

Operation conditions of EUT was according to clause 6 of EN 55014-1.

Frequency range 30MHz – 300MHz was checked and EMI receiver measurement bandwidth was set to 120kHz.



5.4 Test Protocol



		Quasi-peak			Average	
Frequency (MHz)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)
30.00	*	45.0	*	*	35.0	*
35.05	*	45.2	*	*	35.2	*
65.00	*	46.3	*	*	36.3	*
90.00	*	47.2	*	*	37.2	*
180.00	*	50.6	*	*	40.6	*
220.00	*	52.0	*	*	42.0	*
300.00	*	55.0	*	*	45.0	*
Note: * means th	e emission le	evel 10dB be	low the rele	vant limit.		

Remark: 1. Correct Factor = Clamp Factor + Cable Loss, the value was added to Original Receiver Reading by the software automatically.

- 2. Corrected Reading = Original Receiver Reading + Correct Factor
- 3. Margin = Limit Corrected Reading
- 4. If the PK Corrected Reading is lower than AV limit, the AV test can be elided.

Example: Assuming Clamp Factor = 10.00dB, Cable Loss = 2.00dB,

Original Receiver Reading = 10.00dBuV, Limit = 66.00dBuV.

Then Correct Factor = 10.00 + 2.00 = 12.00dB;

Corrected Reading = 10dBuV + 12.00dB = 22.00dBuV;

Margin = 66.00 dBuV - 22.00 dBuV = 44.00 dB.



For Associated ports: NA

		Quasi-peak			Average	
Frequency (MHz)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)
Note: * means th	e emission le	evel 20dB be	low the relev	vant limit.		·

Remark: 1. Correct Factor = LISN Factor + Cable Loss, the value was added to Original Receiver Reading by the software automatically.

- 2. Corrected Reading = Original Receiver Reading + Correct Factor
- 3. Margin = Limit Corrected Reading
- 4. If the PK Corrected Reading is lower than AV limit, the AV test can be elided.

Example: Assuming LISN Factor = 10.00dB, Cable Loss = 2.00dB,

Original Receiver Reading = 10.00dBuV, Limit = 66.00dBuV. Then Correct Factor = 10.00 + 2.00 = 12.00dB; Corrected Reading = 10dBuV + 12.00dB = 22.00dBuV; Margin = 66.00dBuV - 22.00dBuV = 44.00dB.



6. Radiated emission

Test result:

As for in the disturbance power test all emission readings from the EUT are lower than the applicable limits (Table 7) reduced by the margin (Table 8) and the maximum clock frequency is less than 30MHz, the EUT is deemed to comply with the Radiated Emission requirement without test.

6.1 Limit

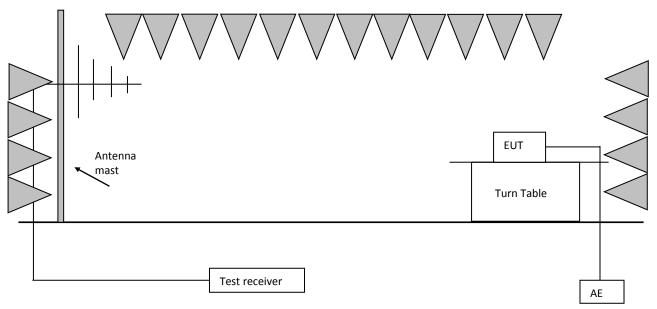
Radiated emission limit from frequency range 30MHz – 1000MHz

PASS

Frequency (MHz)	Permitted limit in dBµV/m (Quasi-peak)	Permitted limit in dBµV/m (Quasi-peak)
	of Measurement Distance	of Measurement Distance
	3m	10m
30 ~ 230	40	30
230 ~ 300	47	37
Notes:		
1. For the measuren	nent distance other than 3m and 10m	n, the limit is varied according to
20dB/10 decades.		

2. The gray rows are selected items.

6.2 Block diagram and test set up

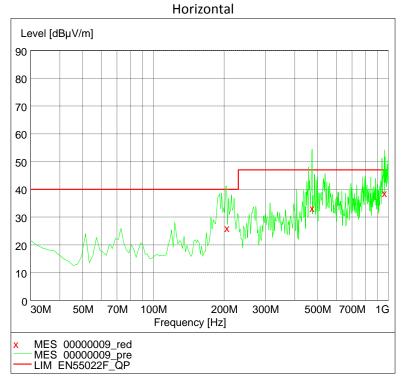


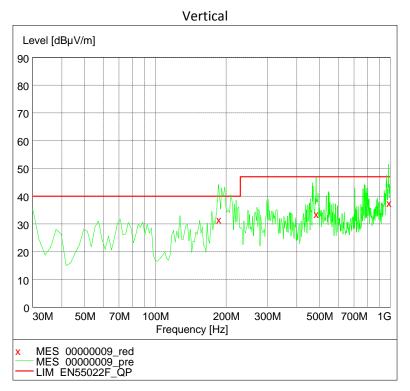
The measurement was applied in a semi-anechoic chamber. Operation conditions of EUT was according to clause 6 of EN 55014-1. Measurement was performed according to clause 10 of CISPR 32. Setting of EUT is according to clause 5.3.4.3 of EN 55014-1. The bandwidth setting on test receiver was 120kHz. The frequency range from 30MHz to 300MHz was checked.



6.3 Test Protocol

EUT operating in working normally mode (not in battery charging mode)







Polarization	Frequency (MHz)	Corrected Reading (dBuV/m)	Limits (dBuV/m)	Margin (dBuV/m)
	53.32	*	40.00	*
	166.07	*	40.00	*
Horizontal	220.50	*	40.00	*
Horizontal	204.94	26.42	40.00	13.58
	473.20	33.58	47.00	13.42
	961.12	38.97	47.00	8.03
	53.32	*	40.00	*
	166.07	*	40.00	*
Vertical	185.51	31.92	40.00	8.08
vertical	482.92	33.84	47.00	13.16
	679.25	*	47.00	*
	982.50	37.95	47.00	9.05

Note: * means margin >10dB.

Remark: 1. Corrected Reading = Original Receiver Reading + Correct Factor

2. Margin = Limit - Corrected Reading

3. If the PK Corrected Reading is lower than AV limit, the AV test can be elided.

Example: Assuming Antenna Factor = 30.20dB/m, Cable Loss = 2.00dB,

Gain of Preamplifier = 32.00dB, Original Receiver Reading = 10.00dBuV, Limit = 40.00dBuV/m. Corrected Reading = 10dBuV + 0.20dB/m = 10.20dBuV/m;

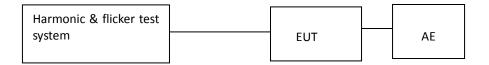
Margin = 40.00dBuV/m - 10.20dBuV/m = 29.80dB.



7. Harmonics

Test result: PASS

7.1 Block Diagram of Test Setup



7.2 Test Setup and Test Procedure

Harmonics of the fundamental current were measured up to 40 order harmonics using a digital power meter with an analogue output and frequency analyser which was integrated in the harmonic & flicker test system. The measurements were carried out under steady conditions.



 \square

Measuring instrumentation according to IEC 61000-4-7:2002+A1:2008

This product is not defined as lighting equipment, and has rated power less than 75W, therefore, no limit apply according to EN 61000-3-2

The EUT is kitchen machines as listed in the scope of IEC 60335-2-14, therefore, is deemed to conform to the harmonic current limits of this standard without further testing.

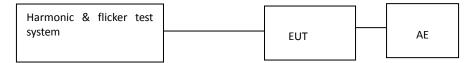
7.3 Test Protocol

tek

8. Voltage Fluctuations-Flicker

Test result: PASS

8.1 **Block Diagram of Test Setup**



8.2 **Test Setup and Test Procedure**

8.2.1 Definition

- Flicker: impression of unsteadiness of visual sensation induced by a light stimulus whose luminance or spectral distribution fluctuates with time.
- Pst: Short-term flicker severity.
- Plt: long-term flicker severity.
- dc: maximum steady state voltage change during an observation period.
- maximum absolute voltage change during an observation period. dmax:
- d(t): time function of the relative r.m.s. voltage change evaluated as a single value for each successive half period between zero-crossings of the source voltage, except during time interval in which the voltage is a steady-state condition for at least 1s.

8.2.2 Test condition

The EUT was set to produce the most unfavorable sequence of voltage changes.

intertek Total Quality. Assured.

8.3 Test Protocol

The tested object operated under the operating condition specified in EN 61000-3-3 The following limits apply

- the value of Pst shall not be greater than 1,0.
- the value of Plt shall not be greater than 0,65.
- Tmax, the accumulated time value of d(t) with a deviation exceeding 3,3 % during a single voltage change at the EUT terminals, shall not exceed 500 ms.
- the maximum relative steady-state voltage change, dc, shall not exceed 3,3 %.
- the maximum relative voltage change dmax, shall not exceed:

4% without additional conditions.

6 % for equipment which is:

- switched manually, or
- switched automatically more frequently than twice per day, and also has either a delayed restart (the delay being not less than a few tens of seconds), or manual restart, after a power supply interruption.
- 7 % for equipment which is:

- attended whilst in use (for example: hair dryers, vacuum cleaners, kitchen equipment such as mixers, garden equipment such as lawn mowers, portable tools such as electric drills), or

- switched on automatically, or is intended to be switched on manually, no more than twice per day, and also has either a delayed restart (the delay being not less than a few tens of seconds) or manual restart, after a power supply interruption.

for manual switch, dmax is measured in accordance with Annex B of standard, average dmax is calculated from 24 times measurement.

According to EN 61000-3-3 clause 6.1 & A.2, the EUT is either unlikely to produce significant voltage fluctuations/flicker or no limit and test were required by technical analysis and sample evaluation on the product.



Immunity Test

Performance criteria

The performance criteria are based on the general criteria of the standard and derived from the product specification

Criterion A: Normal Performance within limits specified by the manufacturer, request or purchaser.

Criterion B: Continue to operate as intended after the test. No degradation of performance or loss of function. During the test degradation of performance is allowed, however no change of actual operating state or stored date.

Criterion C: Temporary loss of function is allowed, provided the function is self-recoverable or can be restored by the operation of the controls.

Categories of apparatus

Category I (fulfill the relevant immunity requirements without testing)

Category II (Shall fulfill the tests: ESD, EFT, Inject current, Surge, Dips)

Category III (Shall fulfill the tests: ESD, EM fields*)

Category IV (Shall fulfill the tests: ESD, EFT, Inject current, Surge, Dips, EM fields)

Note: *only applicable to the ride on toys operating with electronic devices.

intertek

Total Quality. Assured.

9. Electrostatic Discharge (ESD)

Test result: PASS

9.1 Severity Level and Performance Criterion

9.1.1 Test level

1a – Contae	ct discharge	1b – Air discharge		
Level	Test voltage kV	Level	Test voltage kV	
1	2	1	2	
2	4	2	4	
3	6	3	8	
4	8	4	15	
Х	Special	Х	Special	

Notes:

1."X" is an open level. The level has to be specified in the dedicated equipment specification. If higher voltages than those shown are specified, special test equipment may be needed.

2. The gray rows were the selected test level.

9.1.2 Performance Criterion

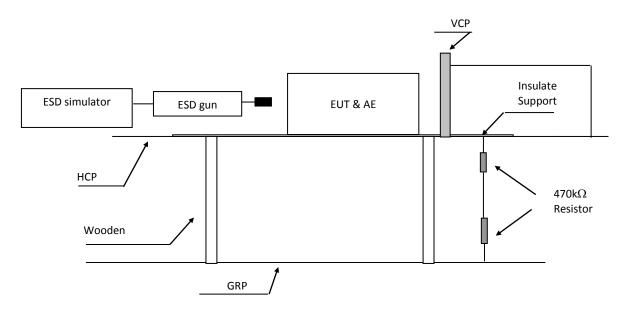
Performance criterion: B

Report No. 191102430SHA-001

Intertek Total Quality. Assured.

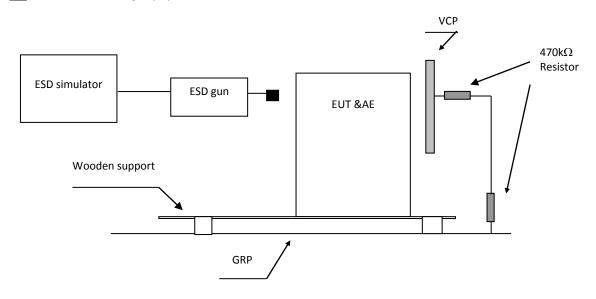
9.2 Block Diagram of Test Setup

For table-top equipment



Note: HCP means <u>H</u>orizontal <u>C</u>oupling <u>P</u>lane VCP means <u>V</u>ertical <u>C</u>oupling <u>P</u>lane GRP means <u>G</u>round <u>R</u>eference <u>P</u>lane Wooden support is a 0.8m height table

For floor standing equipment



Note: VCP means <u>V</u>ertical <u>C</u>oupling <u>P</u>lane GRP means <u>G</u>round <u>R</u>eference <u>P</u>lane Wooden support is a 0.1m height rack



Total Quality. Assured.

9.3 **Test Setup and Test Procedure**

Measurement was performed in shielded room.

Measurement and setting of EUT was applied according to IEC 61000-4-2 Clasuse 7. The test method and equipment was specified by IEC 61000-4-2 with the modifications by EN 55014-2 clause 5.1.

intertek Total Quality. Assured.

9.4 Test Protocol

Test point #	Test level [kV]	Air/ Contact	Polarity (+/-)	Pass/Fail/NA	Comment
А	2/4	Contact	+/-	Pass	All touchable screws of enclosure
В	2/4	Contact	+/-	Pass	Accessible metal parts of the EUT
С	2/4/8	Air	+/-	Pass	Air gap of the switch, button
D	2/4/8	Air	+/-	Pass	The air in-taking opening
E	2/4/8	Air	+/-	Pass	Slots around the EUT

Direct discharges were applied at the following selected points:

Indirect contact discharges were applied to the VCP and the HCP at the following selected points:

For table top equipment

Point	Description	Point	Pass/Fail/NA
HCP f	0,1m from the front of the EUT	Edge of centre, corner on HCP	-
HCP b	0,1m from the back of the EUT	Edge of centre, corner on HCP	-
HCP r	0,1m from the right side of the EUT	Edge of centre, corner on HCP	-
HCP I	0,1m from the left side of the EUT	Edge of centre, corner on HCP	-
VCP f	0,1m from the front of the EUT	Edge of centre, corner on VCP	-
VCP b	0,1m from the back of the EUT	Edge of centre, corner on VCP	-
VCP r	0,1m from the right of the EUT	Edge of centre, corner on VCP	-
VCP I	0,1m from the left of the EUT	Edge of centre, corner on VCP	-

For floor standing equipment

Point	Description	Point	Pass/Fail/NA
VCP f	0,1m from the front of the EUT	Edge of centre, corner on VCP	Pass
VCP b	0,1m from the back of the EUT	Edge of centre, corner on VCP	Pass
VCP r	0,1m from the right of the EUT	Edge of centre, corner on VCP	Pass
VCP I	0,1m from the left of the EUT	Edge of centre, corner on VCP	Pass

Observation: All the functions were operated as normal during and after test. **Conclusion:** The EUT met the requirements of Performance Criterion B.

intertek

Total Quality. Assured.

Electromagnetic field susceptibility 10.

Test result:

10.1 Severity Level and Performance Criterion

Pass

10.1.1 Test level

Level	Test field strength V/m
1	1
2	3
3	10
Х	Special
Notes:	

Notes:

1. X is an open test level. This level may be given in the product specification.

2. The gray row is the selected test level.

10.1.2 Performance Criterion

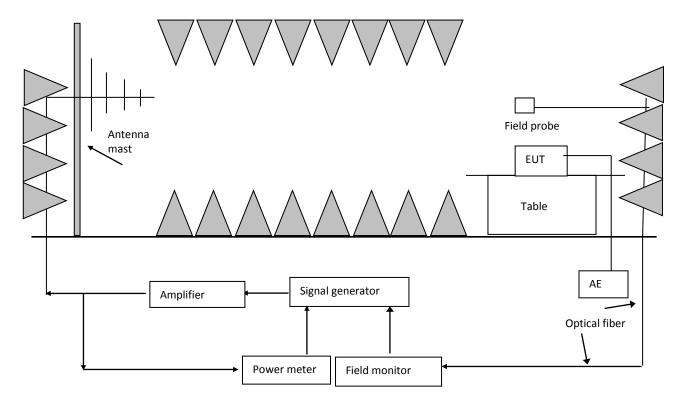
Performance criterion: A



Report No. 191102430SHA-001

Total Quality. Assured.

10.2 Block diagram of test setup



10.3 Test Setup and Test Procedure

Measurement was performed in full-anechoic chamber. Measurement and setting of EUT was applied according to IEC 61000-4-3 clause 7. The test method and equipment was specified by IEC 61000-4-3 with additions and modifications by EN 55014-2 clause 5.5.

10.4 Test Protocol

Test no.:	Frequency (MHz)	Polarization	Test level V/m	Modulation	Exposed location	Pass/Fail/NA	Commen t
1	80-1000	H & V	3	1kHz, 80%, SW, AM, 1% step size	All sides	Pass	-

Observation: All the functions were operated as normal during and after test. **Conclusion:** The EUT met the requirements of Performance Criterion A.

Total Quality. Assured.

Electric Fast Transient/Burst Immunity Test 11.

Test result: PASS

11.1 Severity Level and Performance Criterion

11.1.1 Test level

Open circuit output test voltage (±10%) and repetition rate of the impulses (±20%)							
Level	Input and output	a.c. power ports	Input and output d.c. power ports Signal lines and control lines ports				
	Voltage peak kV	Repetition rate kHz	Voltage peak kV	Repetition rate kHz			
1	0.5	5	0.25	5			
2	1	5	0.5	5			
3	2	5	1	5			
4	4	5	2	5			
Х	Special	Special	Special	Special			
Notes :							

1. "X" is an open level. The level has to be specified in the dedicated equipment specification.

2. The gray rows were the selected test level.

11.1.2 Performance Criterion

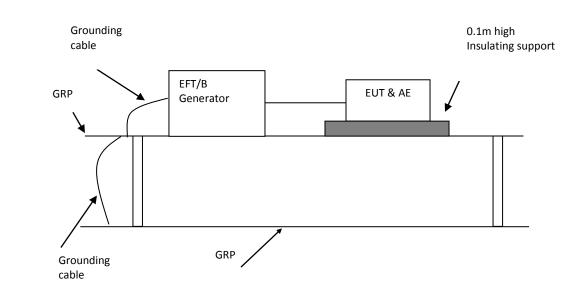
Performance criterion **B**

Total Quality. Assured.

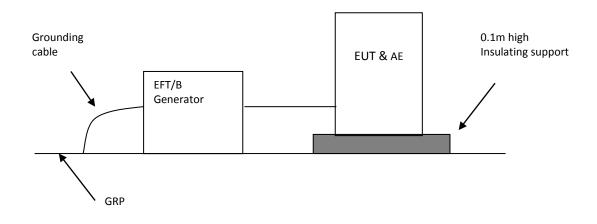
11.2 Block Diagram of Test Setup

11.2.1 Block Diagram for input a.c./d.c. power line

For table-top equipment



Sor floor standing equipment

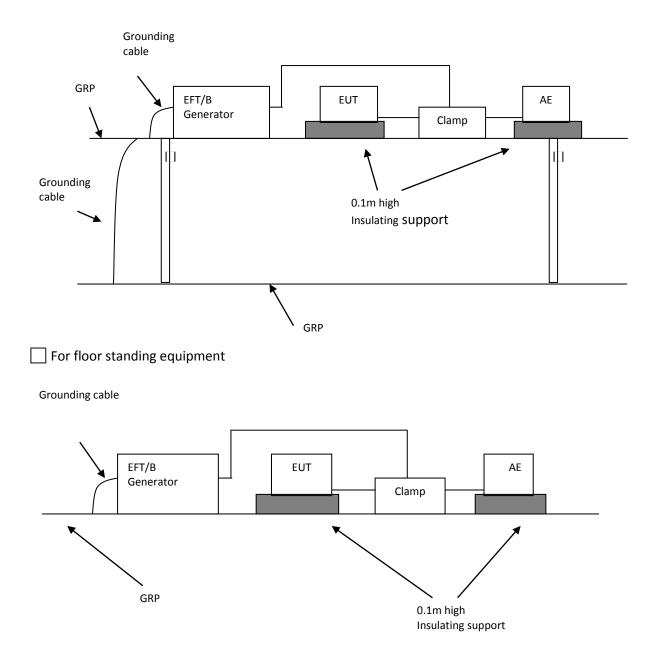




Total Quality. Assured.

11.2.2 Block Diagram for output a.c./d.c. power line or signal/control lines

For table-top equipment



11.3 **Test Setup and Test Procedure**

Measurement was performed in shielded room. Measurement and setting of EUT was applied according to IEC 61000-4-4 clause 7. The test method and equipment was specified by IEC 61000-4-4 with additions and modifications by EN 55014-2 clause 5.2.

Report No. 191102430SHA-001

Intertek Total Quality. Assured.

11.4 Test Protocol

Test No.	Level [kV]	Polarity +/-	Repetition rate kHz	Line for test	Pass/Fail/NA
1	1	+/-	5	a.c. power ports	Pass
2	0.5	+/-	5	d.c. power ports	NA
3	0.5	+/-	5	Signal lines and control lines	NA

Observation: All the functions were operated as normal during and after test. **Conclusion:** The EUT met the requirements of Performance Criterion B.

Total Quality. Assured.

12. Surge Immunity Test

Test result: PASS

12.1 Severity Level and Performance Criterion

12.1.1 Test level

Level	Open-circuit test voltage ±10% kV
1	0.5
2	1.0
3	2.0
4	4.0
X*	Special
Notes: 1."X" is an open class. This level can be sp	pecified in the product Specification

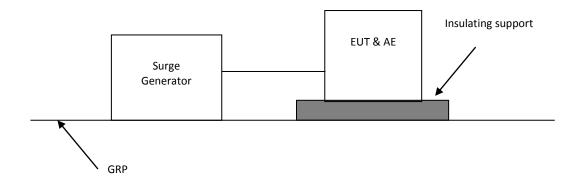
2. The gray rows are the selected level.

12.1.2 Performance Criterion

Performance criterion **B**

Total Quality. Assured.

12.2 Block Diagram of Test Setup



12.3 Test Setup and Test Procedure

Measurement was performed in shielded room. Measurement and setting of EUT was applied according to IEC 61000-4-5 clause 7. The test method and equipment was specified by IEC 61000-4-5 with modifications by EN 55014-2 clause 5.6.

12.4 Test Protocol

Test No.	Level [kV]	Polarity +/-	Angle	Line for test	Pass/Fail/NA
1	1	+	90 ⁰	a.c. Mains (line to earth)	NA
2	1	-	270 ⁰	a.c. Mains (line to earth)	NA
3	1	+	90 ⁰	a.c. Mains (line to line)	Pass
4	1	-	270 ⁰	a.c. Mains (line to line)	Pass
5	2	+	90 ⁰	a.c. Mains (line to earth)	NA
6	2	-	270 ⁰	a.c. Mains (line to earth)	NA

Observation: All the functions were operated as normal during and after test. **Conclusion:** The EUT met the requirements of Performance Criterion B.

Total Quality. Assured.

Immunity to Conducted Disturbances, Induced by Radio-frequency Fields 13.

Test result: PASS

Severity Level and Performance Criterion 13.1

13.1.1 Test level

Level	Level Voltage level (e.m.f.)				
	U ₀ [dB(uV)]	U ₀ (V)			
1	120	1			
2	130	3			
3	140	10			
Х	Special	Special			

1. "X" is an open level. 2. The gray row is the selected test level.

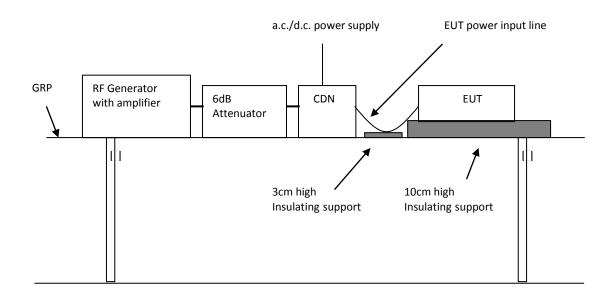
13.1.2 Performance Criterion

Performance criterion: A

Block Diagram of Test Setup 13.2

13.2.1 Block Diagram for a.c./d.c input power line

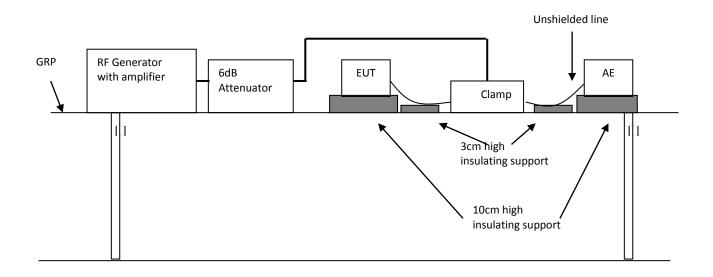
Block Diagram for a.c./d.c input power line



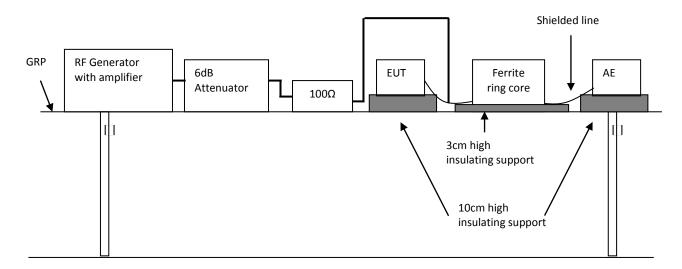


13.2.2 Block Diagram for output a.c./d.c. power line or signal/control lines

Unshielded line



Shielded line



13.3 Test Setup and Test Procedure

Measurement was performed in shielded room. Measurement and setting of EUT was applied according to IEC 61000-4-6 clause 7. The test method and equipment was specified by IEC 61000-4-6 with additions and modifications by EN 55014-2 clause 5.3, 5.4.

intertek Total Quality. Assured.

13.4 Test Protocol

EUT is not required for electromagnetic susceptibility

- [Test	Frequency	Level	Modulation	Injected point	Pass/Fail/NA
	No.	(MHz)	V (r.m.s.)			
	1	0.15~230	3	1kHz, 80%, SW,	a.c. power ports	Pass
				AM,		
				1% step size		
	2	0.15~230	1	1kHz, 80%, SW,	d.c. power ports	-
				AM,		
				1% step size		
	3	0.15~230	1	1kHz, 80%, SW,	signal lines and	-
				AM,	control lines	
				1% step size		

For EUT test Electromagnetic field susceptibility

Test	Frequency	Level	Modulation	Injected point	Pass/Fail/NA
No.	(MHz)	V (r.m.s.)			
1	0.15~80	3	1kHz, 80%, SW,	a.c. power ports	NA
			AM,		
			1% step size		
2	0.15~80	1	1kHz, 80%, SW,	d.c. power ports	-
			AM,		
			1% step size		
3	0.15~80	1	1kHz, 80%, SW,	signal lines and	-
			AM,	control lines	
			1% step size		

Observation: All the functions were operated as normal during and after test. **Conclusion:** The EUT met the requirements of Performance Criterion A.

14. Voltage Dips, Short Interruptions and Voltage Variations Immunity Test

Test result: PASS

14.1 Severity Level and Performance Criterion

14.1.1 Test level

Test level	Voltage dip and short interruptions	Duration (in period)	
% U _T	% U _τ	50Hz	60Hz
0	100	0.5 cycle	0.5 cycle
40	60	10 cycles	12 cycles
70	30	25 cycles	30 cycles

Notes:

1. "*" for 0.5 period, the test shall be made in positive and negative polarity, i.e. starting at 0° and 180°, respectively.

2. "**" means "x" is an open duration. This duration can be given in the product specification. Utilities in Europe have measured dips and short interruptions of duration between ½ a period and 3000 periods, but duration less than 50 periods are most common.

3. If the EUT is tested for voltage dips of 100%, it is generally unnecessary to test for other levels for the same durations. However, for some cases (safeguard systems or electro-mechanical devices) it is not true. The product specification or product committee shall give an indication of the applicability of this note.

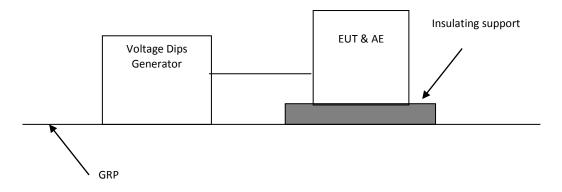
4. The gray rows are selected test level.

14.1.2 Performance Criterion

Performance criterion: C

Total Quality. Assured.

14.2 Block diagram of test setup



14.3 Test Setup and Test Procedure

Measurement was performed in shielded room. Measurement and setting of EUT was applied according to IEC 61000-4-11 clause 7. The test method and equipment was specified by IEC 61000-4-11 with additions and modifications by EN 55014-2 clause 5.7.

14.4 Test Protocol

Test no.	% U _T	Voltage dip and short interruptions % UT	Duration (in periods)	Pass/Fail/NA
1	70	30%	25 cycles at 50Hz	Pass
			30 cycles at 60Hz	NA
2	40	60%	10 cycles at 50Hz	Pass
			12 cycles at 60Hz	NA
3	0	100% pos half cycle	0.5 cycle at 50Hz	Pass
			0.5 cycle at 60Hz	NA
4	0	100% neg half cycle	0.5 cycle at 50Hz	Pass
			0.5 cycle at 60Hz	NA

Observation: At test level of 70%, the EUT worked unsteadily. Once the interference is removed, it recovered its normal mode at once

Conclusion: The EUT met the requirements of Performance Criterion B.



Appendix I: Photograph of equipment under test













END of the report